

Notice of References Cited	Application/Control No. 10/692,516		Applicant(s)/Patent Under Reexamination YEOW ET AL.	
	Examiner VANEL FRENEL		Art Unit 3687	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-2004/0034581	02-2004	Hill et al.	705/28
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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